Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/602,902	HARMLESS ET AL.		
Examiner	Art Unit		
Betsey M. Hoey	1724		

SEARCHED						
Class	Subclass	Date	Examiner			
210	748					
	739					
	760					
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422	105		V			
	119	4/4/05	BMH			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
		DATE	EXMR	
inventor	name	6/6/05	BNA	
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